



Substitute for form 1449/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

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| Application No.: | 10/549,865 |
| Filing Date: | July 28, 2006 |
| First Named Inventor: | Victor Higgs |
| Art Unit: | 2886 |
| Examiner Name: | Isiaka O. Akanbi |
| Attorney Docket No.: | NAN65 US (8037) |

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| Sheet | 1 | of | 5 |
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Examiner
Signature:

/Isiaka Akanbi/

Date
Considered:

04/14/2008

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| Sheet | 2 | of | 5 |
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